

Norwegian Electro-optics Meeting, May 2-4, 2004, Tønsberg

NANO-PHOTONIC INTEGRATED CIRCUITS the promise and the problems

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- Introduction to nano-photonics
- Nano-photonic ICs
- Challenges
 - in the physics
 - in the technology
 - in the packaging





Nano-photonics: what

Photonics:

generation, transport, processing and detection of light

Nano-photonics:

same, whereby light interacts with material features with a scale in the range of a few nm to a few 100 nm (in (one,) two or three dimensions)



Nano-photonics: a broad field

• linear and non-linear response of nano-composite materials

- size of nano-particles<< 1 ® effective medium
- strong surface plasmon resonant enhancement for metallic nanoparticles
- **potential of very strong** $c^{(3)}$ (plasmon enhancement)
- interband transitions in semiconductor nanoparticles
 - quantum dots and wires (size << 1)</p>
 - strong modification of electronic bandstructure
 - **potential of strong** $c^{(3)}$ (electronic enhancement)
- wavelength scale high refractive index contrast structures
 - modification of SpE in wavelength scale microcavities
 - modification of propagation by means of photonic crystals
 - ultra-compact photonic circuits, photonic crystal fiber
 - **potential of strong** $c^{(3)}$ (optical enhancement)

THIS PRESENTATION



- Introduction to nano-photonics
- Nano-photonic ICs
- Challenges
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Photonic Integrated Circuits (PICs)

What ?

- ICs in which sub-components are interconnected by optical waveguides
- sub-components :
 - passive wavelength selective components
 - electrically driven modulators, light sources, optical amplifiers, detectors, wavelength converters...
 - ...



fabrication by wafer-scale micro-electronic technologies

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Photonic Integrated Circu

Why integrate ?

- Economics of wafer scale integration
- Compact implementation of complex functions (systems-on-a-chip)
- Higher performance
- **!!!** Alignment of photonic components automatically ensured by lithographic methods **!!!**





E.g. Double-PHASAR X-connect (TU Delft)

Crossconnects







Ref.: Herben et al., IEEE PTL 10(5), pp. 678-680 (1998)

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Scale difference

| <i>Electronics</i> interconnects gate transistor width | flip-flop | | | |
|---|--|--------------------------------|-------------------------------|-----------------------------|
| | | | | |
| Active opto-electronics Wavelength-scale photonics | L VCSEL | detector ED stripe la 2F | lser R regenera | ıtor |
| | | | | |
| Passive photonicsWavelength-scalephotonicsIIICI | fibre core newidth in arrent PIC | sı co Bend radius | taper pot-size onvertor | AWG in Silica on Silicon |
| | | | | |
| IOOnm 1μm © intec 2004 | 10µm | 100µm | 1mm http://phot | lcm onics.intec.ugent.be |

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PICs: today and future

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Today (InP, Silica-on-Silicon...):
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• size of components on a chip (both functional components
and interconnect components):
10^3 - 10^6 \text{ mm}^2
```

•number of components on a chip: 1 - 10³

Future (10-20 years from now):

 size of components on a chip (both functional components and interconnect components):

1 - 10³ mm²

•number of components on a chip: 10³ - 10⁶



-

Reduce PIC-size / increase density

WE NEED:

Ultra-compact waveguiding with

- Sharp bends (Bend radius < 10mm)
- Compact splitters and combiners
- Short mode-conversion distances
- **Compact wavelength selective functions**
 - Highly dispersive element
 - Small, high-Q resonators
- **Compact non-linear functions**
 - Increase power density by using tight confinement



High refractive index contrast (>2:1)

- High refractive index contrast allows for:
- very tight bends



- compact resonators with low loss
- wide angle mirrors
- very compact mode size
 - --> strong field strength
 --> strong non-linear effects
 - --> small volume to be pumped in active devices
 --> faster and/or lower power
- photonic bandgap effects



R high refractive index contrast is the key for ultra-compact photonic circuits

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Ultra-compact waveguide candidates

Photonic Crystal waveguides:

- in-plane: high contrast photonic crystal defect
- out-of-plane: TIR

Photonic Wires:

- in-plane: high contrast TIR
- out-of-plane: TIR





Guided Bloch mode conditions



Compact bends

Photonic Crystal

• Light is confined by the PBG

Photonic Wire

 Deep etch allows for short bend radius (a few mm)

0

• Corner mirrors



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ndex Contrast





Materials for nanophotonic waveguides

| Si/SiO ₂ (SOI) | In-plane index contrast 3.5 to 1 | Out-of-plane index contrast 3.5 to 1.5 |
|---------------------------|--|--|
| Si/air | 3.5 to 1 | 3.5 to 1 |
| (membrane) GaAs/AlOx | 3.5 to 1 | 3.5 to 1.5 |
| InP/SiO ₂ | 3.3 to 1 | 3.3 to 1.5 |
| SiON/SiO ₂ | 2 to 1.5/1 | 2 to 1.5 |
| GaAs/AlGaAs | 3.5 to 1 | 3.5 to 3.2 |
| InGaAsP/InP | 3.3 to 1 | 3.3 to 3.17 |



Spectral accuracy and geometrical accuracy

High index contrast components:

- interference based filters,



with d the waveguide width (»1)

- cavity resonance wavelength



with d the cavity length (a few 1)

- photonic crystal



with d the hole diameter (»1)





Ultra-compact waveguide candidates

Photonic Crystal waveguides:

- in-plane: high contrast photonic crystal defect
- out-of-plane: TIR

Photonic Wires:

- in-plane: high contrast TIR
- out-of-plane: TIR

Both cases: • feature size : 50-500 nm • required accuracy of features: 1-10 nm NANO-PHOTONIC waveguides



Ring resonator based add-drop filter

Hryniewcz et al.

- Waveguide width: .42-.62mm
- Straight guides: <10 dB/cm
- Bend radius: 4.5 mm











SOI Photonic crystal waveguides

SOI: Good vertical waveguide material

- Top Silicon layer: n = 3.45
- Oxide cladding layer: n=1.45

Fabrication at IMEC

- 248nm deep UV lithography
- Dry etching





Ring resonators in Silicon on Insulator





Introduction to nano-photonics

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- Challenges
 - in the physics

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- in the technology
- in the packaging



Challenges in the physics.

- understand the various loss mechanisms
- high versus low index contrast in the vertical (out-of-plane) direction
- photonic wires versus photonic crystal waveguides
- impact of roughness
- ••





Losses of straight single mode waveguides

| | | index contrast index contrast index contrast | | | |
|---|--|--|---|--------------------------------|--|
| | • | Low in-plane (Lip) | High in-plane (Hip) | In-plane | |
| Low out-of-plane (Lop) index contrast | | SOS (<0.1dB/cm) InP (1 dB/cm) (AI)GaAs (1 dB/cm) | InP (wire: 50 d InP (crystal: few 10 (Al)GaAs (wire: 10 | B/cm) 00 dB/cm) 0 dB/cm) | |
| | High out-of-plane (Hop) index contrast | SOI GaAs/AlOx | SOI (wire: 2-4 dB/cm) SOI (crystal: 7-15 dB/cm) GaAs/AlOx | | |
| | Out-of-plane index contrast | Conventional photonic ICs | Future nanophotonic IC | S | |

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osses of straight single mode waveguides

From state-of-the-art experimental results, it seems that:

- high (out-of-plane) index contrast is an order of magnitude better than low (out-ofplane) index contrast
- photonic wire is an order of magnitude better than photonic crystal

WHY?



Losses in compact waveguides

Photonic Crystal

- **Perfect in-plane guiding**
- Lack of vertical guiding in holes gives out-of-plane scattering losses
- irregularities will add more losses

Photonic Wire

- Perfect guiding in a perfectly made structure
- No PBG to stop the inplane scattering at irregularities





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Out-of-plane scattering losses

Question:

To keep out-of-plane scattering low, is it better to have low or high vertical index contrast in your layer structure?

Conventional waveguide (e.g. GaAs-AlGaAs-structure)

Semiconductor 'membrane', Silicon-on-Insulator, GaAs-AlOx





low contrast: 3.5 to 3.2 (∆ε ≈2) © intec 2004



High versus low vertical contrast

Low refractive index contrast

- Waveguide mode is above the light line
- Losses at discontinuities similar to losses in straight sections

High refractive index contrast

- Guided Bloch mode below the light line and does not scatter
- Discontinuities can scatter <u>massively</u>, unless properly designed







FIR guide versus photonic crystal guide







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Technologies for nano-photonic ICs

NANO-PHOTONIC waveguides

feature size : 50-500 nm

required accuracy of features: 1-10 nm (or better)

large field (at least cm²)

alignment to previous patterns: 100 nm accuracy

- maskless research and prototype technologies
 - e-beam lithography + reactive ion etching
 - focussed ion beam (FIB) etching
- mask-based manufacturing technologies
 - deep UV optical lithography + dry etching





Nanophotonics by means of CMOS technology

Why?

- Processes with very high performance and reproducibility
- Market for photonic ICs is relatively small: you cannot afford a dedicated fab
- Fabless company model can work



MEC's Deep UV Lithography for CMOS

248nm excimer laser Lithography

- ASML PAS 5500/300 Stepper and PAS 5500/750 Step-andscan Stepper
- Automated in-line processing (spin-coating, pre- and post-bake, development)
- 4X reticles
- Standard process







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Racetrack resonators

- symmetrically coupled
- wire width = 450nm, gap = 250nm
- **k** » 0.3 , ring loss » 7.5dB/mm
- finesse 28, Q » 3200



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normalized transmission [dB]

pass

10µm

Ring resonator

- Ring radius = 5mm
- TE polarisation
- Q » 8000, Finesse » 88
- FWHM » 0.19nm
- FSR = 17nm







Lots of holes on a 200 mm wafer





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Photonic crystal Waveguides

W3 waveguide

- pitch = 460nm
- hole Ø = 290nm





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Fibre coupling

InP ridge wg

Mode mismatch between waveguide and fibre





SM-fibre core

http://photonics.intec

d mm

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Coupling to fiber

- polymer on SOI taper (POSOI)
- NTT Notomi
- < 0.5dB coupling loss between
 0.2mm x 0.4mm waveguide and 4mm Æ fiber

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Surface fiber coupler

- Coupling by butt coupled fiber
- Coupling area: 10x10 micron
- Allows wafer-level testing
- tolerant alignment
- coupling efficiency (theory): 30-80%
- coupling efficiency to butt-coupled fiber (experim.): 25-33% (Ghent University- IMEC)
- UCLA (CLEO, June 2003): higher efficiency by means of extra layers above grating





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Single mode fiber core

Shallow fibre couplers



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Fibre Coupler Measurement setup



Fibre couplers

Fibre to fibre:

- -14 dB maximum transmission
- 60nm 6dB bandwidth

Per coupler: 1500 1525 1550 1575 1600 wavelength [nm] • 60nm 3dB bandwidth -14dB -15 Pout [dB] -20 >60nm -25 -30 -35 -40 © intec 2004 http://photonics.intec.ugent.be





nterferometric couplers





A12 -00

- much shorter than adiabatic tapers
- optimized by means of genetic algorithms



2D grating fiber couple

Fiber to waveguide interface for polarisation independent photonic integrated circuit

- 2D grating
- couples each fiber polarisation in its own waveguide
- in the waveguides the polarisation is the same (TE)
- Allows for <u>polarisation</u> <u>diversity</u> approach





Experimental results

Fabrication

- SOI: 220nm Si / 1000nm SiO₂
- Etch depth: 90nm
- Square lattice of holes: 580nm period





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Conclusions

• Nano-photonic ICs based upon wavelength scale high index contrast structures have a huge potential and can bring LSI-level integration into the world of photonics.

• The understanding of the physics and the required technologies are all making rapid progress.

• Nano-photonic ICs can take advantage of the nanostructuring technologies developed for next-generation micro-electronics.



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Acknowledgements

the European PICCO project



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- the SPT-division at IMEC
- the photonics group at Ghent University-IMEC



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